

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHIN ET AL.	
		Examiner Eric D. Bertram	Art Unit 3766	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,313,962	05-1994	Obenchain, Theodore G.	128/898
*	B	US-5,571,161	11-1996	Starksen, Niel F.	607/122
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 00/40159 A1	07-2000	World Intellect	YEUNG et al.	A61B 17/064
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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